Hybrid 7p159 Traveler

June 8, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 7P159 has die: 239-117 239-118 239-119 239-120 239-121 239-123 239-124

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 7p159 classification info. Created 09:17:43 06/08/00

Hybrid 7p159 quality: fair
Chip classification: good good good good fair good fair
Bad channels (chip-channel): 4-114 6-11
Bad cells: none
Random bad capacitors (chip-cell-channel): 4-23-44
Channels at pedestal needed for DCMS: 31.6 28.6 31.6 31.6 29.3 31.6 30.5
```

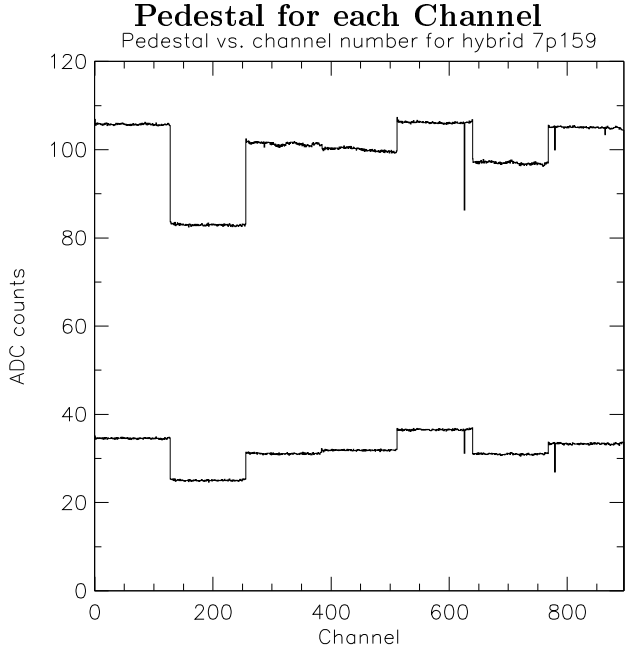
4 Comments

Encapsulated. FE DV finger gold bonds. HV tested. Chip 2 replaced.

5 Pedestal

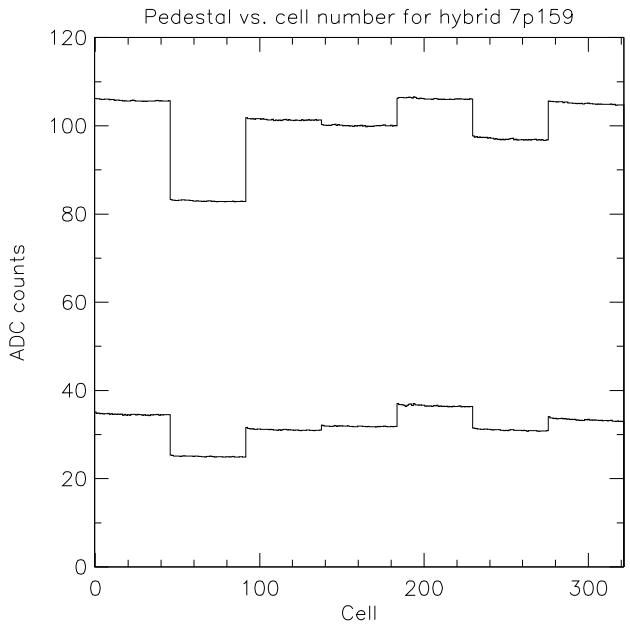
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

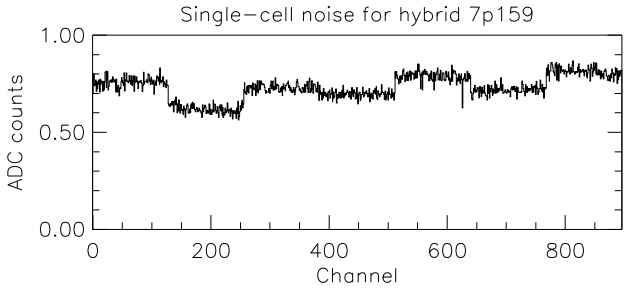
Pedestal vs. Pipeline Cell ID

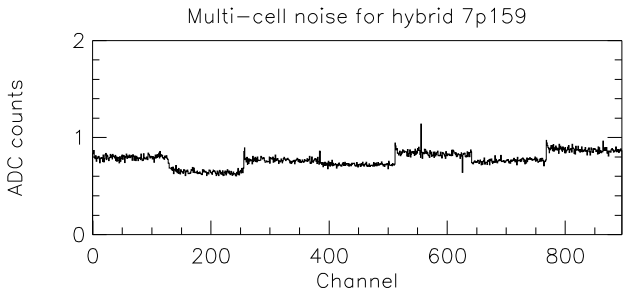


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

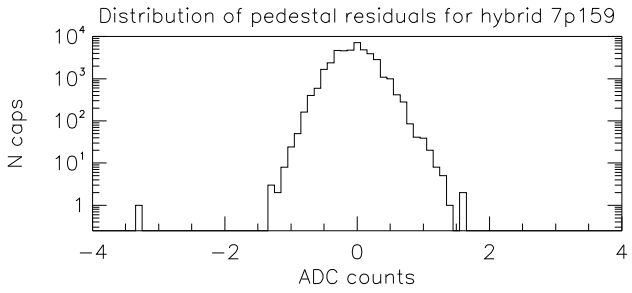
RMS Noise

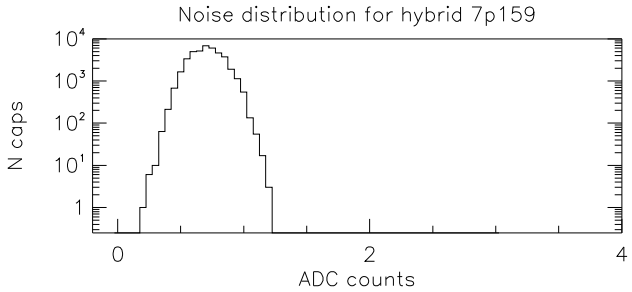




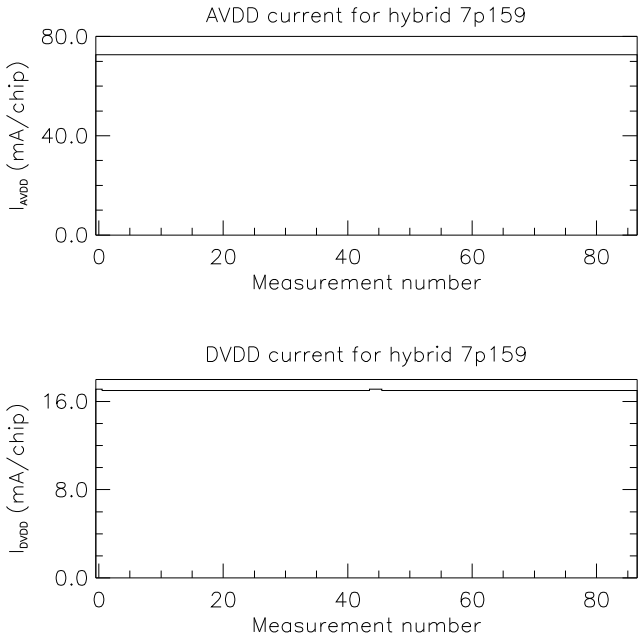
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in